Search Notes		
		١
		l

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/717,870	BEYER ET AL.	
Examiner	Art Unit	
Emeka Ebirim	2166	

SEARCHED			
Class	Subclass	Date	Examiner
707	updated	8/24/2006	EE
*			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
	t search (see earch notes)	8/25/2006	EE

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST Search	8/24/2006	EE
Consulted Pham Khanh (primary)	8/24/2006	EE
Google search	8/24/2006	EE
ACM search	8/24/2006	EE